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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Banqiu Wu et al.

Serial No. : 10/644,358

Filing Date : August 20, 2003

Title : ENDPOINT DETECTION OF PLASMA-ASSISTED
ETCH PROCESS

Examiner : Stephen D. Rosasco

Group Art Unit : 1756

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STATUS INQUIRY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicant respectfully inquiries as to the status of the above-identified application.

The last correspondence received from the U.S. Patent Office was the Notice of Publication of Application dated February 24, 2005. To date we have not received any further correspondence.

Respectfully submitted,

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August 17, 2005

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